SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

- UBT™ (Universal Bus Transceiver)
   Combines D-Type Latches and D-Type
   Flip-Flops for Operation in Transparent,
   Latched, Clocked, or Clock-Enabled Mode
- State-of-the-Art Advanced BiCMOS
   Technology (ABT) Widebus™ Design for
   2.5-V and 3.3-V Operation and Low
   Static-Power Dissipation
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 2.3-V to 3.6-V V<sub>CC</sub>)
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   <0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- High-Drive (-24/24 mA at 2.5-V and -32/64 mA at 3.3-V V<sub>CC</sub>)
- I<sub>off</sub> and Power-Up 3-State Support Hot Insertion
- Use Bus Hold on Data Inputs in Place of External Pullup/Pulldown Resistors to Prevent the Bus From Floating
- Auto3-State Eliminates Bus Current Loading When Output Exceeds V<sub>CC</sub> + 0.5 V
- Flow-Through Architecture Facilitates
   Printed Circuit Board Layout
- Distributed V<sub>CC</sub> and GND Pin Configuration Minimizes High-Speed Switching Noise
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), Thin Very Small-Outline (DGV) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Package

NOTE: For tape and reel order entry:

The DGGR package is abbreviated to GR and the DGVR package is abbreviated to VR.

# description

The 'ALVTH16601 devices are 18-bit universal bus transceivers designed for 2.5-V or 3.3-V  $V_{CC}$  operation, but with the capability to provide a TTL interface to a 5-V system environment.

The devices combine D-type latches and D-type flip-flops to allow data flow in transparent, latched, and clocked modes.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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# TEXAS INSTRUMENTS

SN54ALVTH16601 . . . WD PACKAGE SN74ALVTH16601 . . . DGG, DGV, OR DL PACKAGE (TOP VIEW)

			1
OEAB [	I₁ ∪	56	CLKENAB
LEAB [	2	55	CLKAB
A1 [	3	54	<u>Б</u> в1
GND [	4	53	GND
A2 [	5	52	B2
A3 [	6	51	] B3
v <sub>cc</sub> [	7	50	₫ v <sub>cc</sub>
A4 [		49	] B4
A5 [	9	48	] B5
A6 [	10	47	] B6
GND [	11	46	] GND
A7 [	12	45	] B7
A8 [	13	44	] B8
A9 [	14	43	<b>]</b> B9
A10 [	15	42	B10
A11 [	16	41	B11
A12 [	17	40	B12
GND [	18	39	] GND
A13 [	19	38	B13
A14 [	20	37	B14
A15 [	21	36	B15
v <sub>cc</sub> [	22	35	] v <sub>cc</sub>
A16 [	23	34	B16
A17 [	24	33	<b>]</b> B17
GND [	25	32	] GND
A18 [	26	31	] B18
OEBA [	27	30	CLKBA_
LEBA [	28	29	CLKENBA

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

### description (continued)

Data flow in each direction is controlled by output-enable ( $\overline{OEAB}$  and  $\overline{OEBA}$ ), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock can be controlled by the clock-enable ( $\overline{CLKENAB}$  and  $\overline{CLKENBA}$ ) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB. Output enable  $\overline{OEAB}$  is active low. When  $\overline{OEAB}$  is low, the outputs are active. When  $\overline{OEAB}$  is high, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B, but uses OEBA, LEBA, CLKBA, and CLKENBA.

This device is fully specified for hot-insertion applications using  $I_{off}$  and power-up 3-state. The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.

When  $V_{CC}$  is between 0 and 1.2 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.2 V,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54ALVTH16601 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALVTH16601 is characterized for operation from –40°C to 85°C.

#### **FUNCTION TABLE**†

	I	NPUTS			OUTPUT
CLKENAB	OEAB	LEAB	CLKAB	Α	В
Х	Н	Χ	Χ	Χ	Z
Х	L	Н	Χ	L	L
Х	L	Н	Χ	Н	Н
н	L	L	Χ	Χ	в <sub>0</sub> ‡
н	L	L	Χ	X	в <sub>0</sub> ‡ в <sub>0</sub> ‡
L	L	L	$\uparrow$	L	L
L	L	L	$\uparrow$	Н	Н
L	L	L	L or H	Χ	в <sub>0</sub> ‡

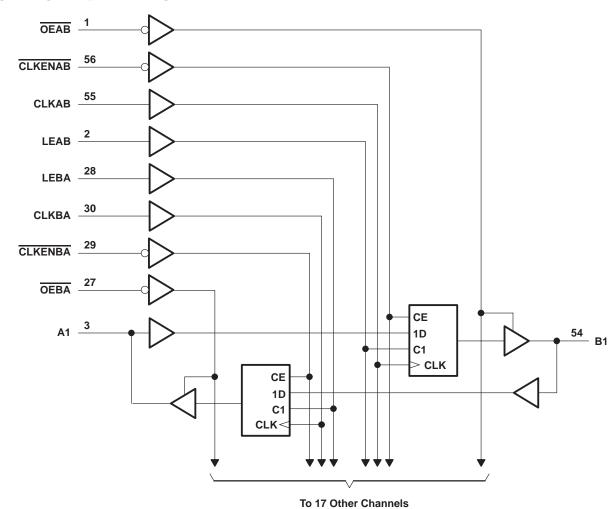
<sup>†</sup> A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, CLKBA, and CLKENBA.



<sup>&</sup>lt;sup>‡</sup> Output level before the indicated steady-state input conditions were established

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

# logic diagram (positive logic)





SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 4.6 V
Input voltage range, V <sub>I</sub> (see Note 1)	
Voltage range applied to any output in the high or power-off state, V <sub>O</sub> (see Note 1)	$-0.5 \text{ V to 7 V}$
Output current in the low state, IO: SN54ALVTH16601	96 mA
SN74ALVTH16601	128 mA
Output current in the high state, I <sub>O</sub> : SN54ALVTH16601	–48 mA
SN74ALVTH16601	–64 mA
Input clamp current, $I_{ K }(V_1 < 0)$	–50 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): DGG package	
DGV package	86°C/W
DL package	74°C/W
Storage temperature range, T <sub>stq</sub>	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

# recommended operating conditions, $V_{CC}$ = 2.5 V $\pm$ 0.2 V (see Note 3)

			SN54	ALVTH1	6601	SN74	ALVTH1	6601	UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	UNIT
VCC	Supply voltage		2.3		2.7	2.3		2.7	V
VIH	High-level input voltage		1.7		7	1.7			V
V <sub>IL</sub>	Low-level input voltage			Š	0.7			0.7	V
VI	Input voltage		0	Vcc	5.5	0	VCC	5.5	V
loн	High-level output current			1	-6			-8	mA
lai	Low-level output current			2	6			8	mA
lOL	Low-level output current; current duty cycle ≤	50%; f≥1 kHz	20,	5	18			24	IIIA
Δt/Δν	Input transition rise or fall rate	Outputs enabled	Q		10			10	ns/V
Δt/ΔV <sub>CC</sub>	Power-up ramp rate		200			200			μs/V
T <sub>A</sub>	Operating free-air temperature		-55		125	-40		85	°C

NOTE 3: All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

# recommended operating conditions, $V_{\mbox{\footnotesize{CC}}}$ = 3.3 V $\pm$ 0.3 V (see Note 3)

			SN54	ALVTH1	6601	SN74/	ALVTH1	6601	UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	UNIT
VCC	Supply voltage		3		3.6	3		3.6	V
VIH	High-level input voltage		2		1/2	2			V
V <sub>IL</sub>	Low-level input voltage			Ś	0.8			0.8	V
VI	Input voltage		0	VCC	5.5	0	VCC	5.5	V
IOH	High-level output current			1	-24			-32	mA
lai	Low-level output current			2	24			32	mA
lor	Low-level output current; current duty cycle ≤	50%; f≥1 kHz	Q	3	48			64	IIIA
Δt/Δν	Input transition rise or fall rate	Outputs enabled	Q		10			10	ns/V
Δt/ΔV <sub>CC</sub>	Power-up ramp rate		200			200			μs/V
TA	Operating free-air temperature	·	-55		125	-40		85	°C

NOTE 3: All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

# electrical characteristics over recommended operating free-air temperature range, $V_{\text{CC}}$ = 2.5 V $\pm$ 0.2 V (unless otherwise noted)

DA	RAMETER	TEST CO	ONDITIONS	SN54	ALVTH1	6601	SN74	ALVTH1	6601	UNIT
PA	RAWETER	1251 00	NUTTIONS	MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
VIK		$V_{CC} = 2.3 \text{ V},$	$I_I = -18 \text{ mA}$			-1.2			-1.2	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V},$	I <sub>OH</sub> = -100 μA	V <sub>CC</sub> -0	.2		VCC-0	.2		
Vон		V <sub>CC</sub> = 2.3 V	$I_{OH} = -6 \text{ mA}$	1.8						V
		VCC = 2.5 V	$I_{OH} = -8 \text{ mA}$				1.8			
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V},$	$I_{OL} = 100 \mu\text{A}$			0.2			0.2	
			$I_{OL} = 6 \text{ mA}$			0.4				
VOL		V <sub>CC</sub> = 2.3 V	$I_{OL} = 8 \text{ mA}$						0.4	V
		VCC = 2.3 V	I <sub>OL</sub> = 18 mA			0.5				
			I <sub>OL</sub> = 24 mA						0.5	
V <sub>RST</sub> ‡		V <sub>CC</sub> = 2.7 V	$I_O = 1 \text{ mA},$ $V_I = V_{CC} \text{ or GND}$			0.55			0.55	٧
	Control innuts	$V_{CC} = 2.7 \text{ V},$	V <sub>I</sub> = V <sub>CC</sub> or GND			±1			±1	
	Control inputs	V <sub>CC</sub> = 0 or 2.7 V,	V <sub>I</sub> = 5.5 V		2/4	10			10	
l <sub>l</sub>			V <sub>I</sub> = 5.5 V		7	10			10	μΑ
	A or B ports	$V_{CC} = 2.7 \text{ V}$	$V_I = V_{CC}$		2	1			1	
			V <sub>I</sub> = 0	C	3	<b>-</b> 5			<b>–</b> 5	
l <sub>off</sub>		$V_{CC} = 0$ ,	$V_I$ or $V_O = 0$ to 4.5 $V$	0					±100	μΑ
I <sub>BHL</sub> §		$V_{CC} = 2.3 \text{ V},$	V <sub>I</sub> = 0.7 V		115			115		μΑ
IBHH		$V_{CC} = 2.3 \text{ V},$	V <sub>I</sub> = 1.7 V		-10			-10		μΑ
IBHLO#	‡	$V_{CC} = 2.7 \text{ V},$	$V_I = 0$ to $V_{CC}$	300			300			μΑ
Івнно	I	$V_{CC} = 2.7 \text{ V},$	$V_I = 0$ to $V_{CC}$	-300			-300			μΑ
lEX☆		$V_{CC} = 2.3 \text{ V},$	V <sub>O</sub> = 5.5 V			125			125	μΑ
I <sub>OZ(PU</sub>	/PD)□	$V_{CC} \le 1.2 \text{ V}, V_O = \underline{0.5} \text{ V}$ $V_I = \text{GND or } V_{CC}, \overline{OE} =$	to V <sub>CC</sub> , don't care			±100			±100	μА
		V <sub>CC</sub> = 2.7 V,	Outputs high		0.04	0.1		0.04	0.1	
ICC		$I_{O} = 0$ ,	Outputs low		2.5	4.5		2.5	4.5	mA
		$V_I = V_{CC}$ or GND	Outputs disabled		0.04	0.1		0.04	0.1	
Ci		$V_{CC} = 2.5 \text{ V},$	V <sub>I</sub> = 2.5 V or 0		3			3		pF
C <sub>io</sub>		$V_{CC} = 2.5 \text{ V},$	$V_0 = 2.5 \text{ V or } 0$		7			7		pF

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 2.5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



<sup>&</sup>lt;sup>‡</sup> Data must not be loaded into the flip-flops/latches after applying power.

<sup>§</sup> The bus-hold circuit can sink at least the minimum low sustaining current at V<sub>IL</sub> max. I<sub>BHL</sub> should be measured after lowering V<sub>IN</sub> to GND and then raising it to V<sub>IL</sub> max.

The bus-hold circuit can source at least the minimum high sustaining current at VIH min. IBHH should be measured after raising VIN to VCC and then lowering it to VIH min.

<sup>#</sup> An external driver must source at least I<sub>BHLO</sub> to switch this node from low to high.

An external driver must sink at least IBHHO to switch this node from high to low.

<sup>☆</sup>Current into an output in the high state when V<sub>O</sub> > V<sub>CC</sub>

<sup>□</sup> High-impedance state during power up or power down

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

# electrical characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted)

D/	ARAMETER	TEST (	CONDITIONS	SN54	ALVTH1	6601	SN74	ALVTH1	6601	UNIT
Ε/	ARAMETER	lE31 (	CONDITIONS	MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
٧ıK		$V_{CC} = 3 V$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
		$V_{CC} = 3 \text{ V to } 3.6 \text{ V},$	$I_{OH} = -100  \mu A$	V <sub>CC</sub> -0	.2		V <sub>CC</sub> -0.	.2		
Vон		V <sub>CC</sub> = 3 V	$I_{OH} = -24 \text{ mA}$	2						V
		VCC = 3 V	$I_{OH} = -32 \text{ mA}$				2			
		$V_{CC} = 3 \text{ V to } 3.6 \text{ V},$	I <sub>OL</sub> = 100 μA			0.2			0.2	
			$I_{OL} = 16 \text{ mA}$						0.4	
VOL			$I_{OL} = 24 \text{ mA}$			0.5				V
VOL		VCC = 3 V	$I_{OL} = 32 \text{ mA}$						0.5	v
			$I_{OL} = 48 \text{ mA}$			0.55				
			$I_{OL} = 64 \text{ mA}$						0.55	
V <sub>RST</sub>	‡	V <sub>CC</sub> = 3.6 V	$I_O = 1 \text{ mA},$ $V_I = V_{CC} \text{ or GND}$			0.55			0.55	V
	Control innuts	V <sub>CC</sub> = 3.6 V,	V <sub>I</sub> = V <sub>CC</sub> or GND		24	±1			±1	
	Control inputs	$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V <sub>I</sub> = 5.5 V		7	10			10	
II			V <sub>I</sub> = 5.5 V		2	10			10	μΑ
	A or B ports	V <sub>CC</sub> = 3.6 V	$V_I = V_{CC}$	Ć	3	1			1	
			V <sub>I</sub> = 0	Q		<b>-</b> 5			<b>–</b> 5	
l <sub>off</sub>		$V_{CC} = 0$ ,	$V_I$ or $V_O = 0$ to 4.5 $V$						±100	μΑ
I <sub>BHL</sub> §		$V_{CC} = 3 V$ ,	V <sub>I</sub> = 0.8 V	75			75			μΑ
IBHH		$V_{CC} = 3 V$ ,	V <sub>I</sub> = 2 V	-75			-75			μΑ
IBHLO	) <sup>#</sup>	$V_{CC} = 3.6 \text{ V},$	$V_I = 0$ to $V_{CC}$	500			500			μΑ
Івнно		$V_{CC} = 3.6 \text{ V},$	$V_I = 0$ to $V_{CC}$	-500			-500			μΑ
lEX☆		$V_{CC} = 3 V$	$V_0 = 5.5 V$			125			125	μΑ
I <sub>OZ(PI</sub>	U/PD)□	$V_{CC} \le 1.2 \text{ V}, V_{O} = \frac{0.5}{\text{OE}}$ $V_{I} = \text{GND or } V_{CC}, \overline{\text{OE}}$	V to V <sub>CC</sub> , = don't care			±100			±100	μΑ
		V <sub>CC</sub> = 3.6 V,	Outputs high		0.06	0.1		0.06	0.1	
ICC		$I_{O}=0$ ,	Outputs low		3.5	5		3.5	5	mA
		$V_I = V_{CC}$ or GND	Outputs disabled		0.06	0.1		0.06	0.1	
∆ICC◊		$V_{CC} = 3 \text{ V to } 3.6 \text{ V, Or}$ Other inputs at $V_{CC}$ or	e input at V <sub>CC</sub> – 0.6 V, GND			0.4			0.4	mA
Ci		V <sub>CC</sub> = 3.3 V,	V <sub>I</sub> = 3.3 V or 0		3			3		pF
C <sub>io</sub>		V <sub>CC</sub> = 3.3 V,	V <sub>O</sub> = 3.3 V or 0		7			7		pF
								-		

 $<sup>\</sup>uparrow$  All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.



<sup>&</sup>lt;sup>‡</sup> Data must not be loaded into the flip-flops/latches after applying power.

<sup>§</sup> The bus-hold circuit can sink at least the minimum low sustaining current at V<sub>IL</sub> max. I<sub>BHL</sub> should be measured after lowering V<sub>IN</sub> to GND and then raising it to V<sub>IL</sub> max.

The bus-hold circuit can source at least the minimum high sustaining current at V<sub>IH</sub> min. I<sub>BHH</sub> should be measured after raising V<sub>IN</sub> to V<sub>CC</sub> and then lowering it to V<sub>IH</sub> min.

<sup>#</sup> An external driver must source at least IBHLO to switch this node from low to high.

An external driver must sink at least IBHHO to switch this node from high to low.

 $<sup>\</sup>star$ Current into an output in the high state when  $V_O > V_{CC}$ 

<sup>□</sup> High-impedance state during power up or power down

<sup>♦</sup> This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 2.5 V $\pm$ 0.2 V (unless otherwise noted) (see Figure 1)

				SN54ALVT	H16601	SN74ALVT	H16601	UNIT
				MIN	MAX	MIN	MAX	UNII
fclock	Clock frequency				150		150	MHz
	Pulse duration	LE high		1.8		1.8		20
t <sub>W</sub>	Pulse duration	CLK high or low		2.3		2.3		ns
		A B h - ( OL)(^	Data high	4		4		
		A or B before CLK↑	Data low	5.2		5.2		
١.	u Setup time	. 5. ( .5.	CLK high	0.7	EN	0.7		
t <sub>su</sub>		A or B before LE↓	CLK low	0.9	Ty.	0.9		ns
1			Data high	1.7, 0		1.7		
		CLKEN before CLK↑	Data low	2.3		2.3		
		A B - 4 O   K^	Data high	0.5		0.5		
		A or B after CLK↑	Data low	0.5		0.5		
		A an D affan I E l	CLK high	2.3		2.3		
th	h Hold time	A or B after LE↓	CLK low	2.4		2.4		ns
		OLICEN - (1 OLIC	Data high	0.5		0.5		
		CLKEN after CLK↑	Data low	0.5		0.5		

# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 2)

				SN54ALVT	H16601	SN74ALVT	H16601	UNIT
				MIN	MAX	MIN	MAX	UNII
fclock	Clock frequency				150		150	MHz
	Dulas direction	LE high		1.8		1.8		
t <sub>W</sub>	Pulse duration	CLK high or low		2.3		2.3		ns
		A == B t = (=== 01.14)	Data high	2.4		2.4		
		A or B before CLK↑	Data low	3.8		3.8		
1.	Catua tima	A B b - ( 1 E l	CLK high	1	EN	1		
t <sub>su</sub>	Setup time	A or B before LE↓	CLK low	0.6	Ty.	0.6		ns
			Data high	1.4,0		1.4		
		CLKEN before CLK↑	Data low	1.9		1.9		
		<b>1</b>	Data high	0.5		0.5		
		A or B after CLK↑	Data low	0.5		0.5		
1.	Halden	A D - ((   E	CLK high	2		2		
th	Hold time	A or B after LE↓	CLK low	2.3		2.3		ns
		CLICEN of an OLIC	Data high	0.6		0.6		
		CLKEN after CLK↑	Data low	0.5		0.5		

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

# switching characteristics over recommended operating free-air temperature range, $C_L$ = 30 pF, $V_{CC}$ = 2.5 V $\pm$ 0.2 V (unless otherwise noted) (see Figure 1)

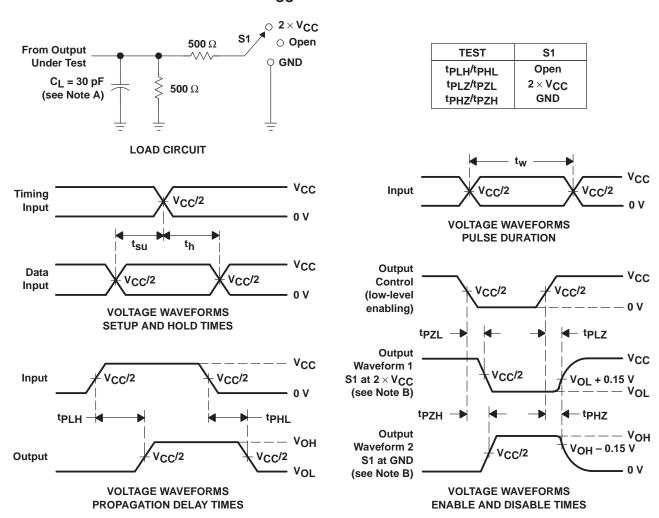
PARAMETER	FROM	то	SN54ALV	ГН16601	SN74ALVT	H16601	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	UNIT
fmax			150		150		MHz
t <sub>PLH</sub>	B or A	A or B	1.1	<u>4</u> .1	1.1	4.1	ns
t <sub>PHL</sub>	D OI A	AOID	1.6	4.8	1.6	4.8	115
<sup>t</sup> PLH	LEBA or LEAB	A or B	2.1	5	2.1	5	ns
<sup>t</sup> PHL	LEDA OI LEAD	AOID	2.4	5.4	2.4	5.4	115
<sup>t</sup> PLH	CLKBA or CLKAB	A or B	2	5	2	5	ns
t <sub>PHL</sub>	CLNBA OF CLNAB	AOIB	2.5	5.9	2.5	5.9	115
<sup>t</sup> PZH	OEBA or OEAB	A or B	2 1.2	4.8	1.2	4.8	ns
t <sub>PZL</sub>	OEBA OF OEAB	AUID	1	4.6	1	4.6	115
<sup>t</sup> PHZ	OEBA or OEAB	A or B	1.2	5.2	1.2	5.2	ns
tPLZ	OEBA OI OEAB	AOID	1	3.9	1	3.9	113

# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	SN54ALV	ГН16601	SN74ALVT	H16601	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	UNIT
fmax			150		150		MHz
t <sub>PLH</sub>	D A	A or B	1.4	<b>3</b> .9	1.4	3.9	20
t <sub>PHL</sub>	B or A	AUID	1.1	3.9	1.1	3.9	ns
t <sub>PLH</sub>	LEBA or LEAB	A or B	2	4.6	2	4.6	ns
t <sub>PHL</sub>	LEBA OF LEAB	AUIB	2.1	4.6	2.1	4.6	115
<sup>t</sup> PLH	CLKBA or CLKAB	A or B	1.9	4.5	1.9	4.5	ns
<sup>t</sup> PHL	CLNBA OI CLNAB	AOIB	2.2	4.6	2.2	4.6	115
<sup>t</sup> PZH	OEBA or OEAB	A or B	Q 1	4.2	1	4.2	ns
t <sub>PZL</sub>	OEBA OF OEAB	AUID	1	4.4	1	4.4	110
<sup>t</sup> PHZ	OEBA or OEAB	A or B	1.8	5.3	1.8	5.3	ns
t <sub>PLZ</sub>	OEDA UT OEAB	AUIB	1.7	4.6	1.7	4.6	115

SCES143A - SEPTEMBER 1998 - REVISED JULY 1999

### PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 V \pm 0.2 V$



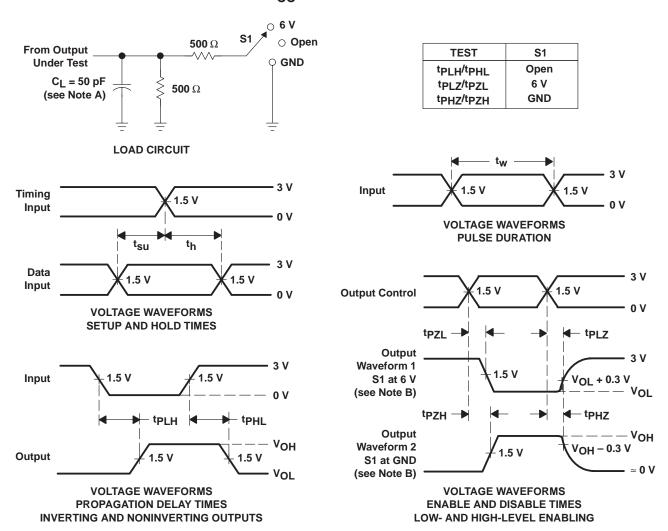
NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \Omega$ ,  $t_f \leq$  2 ns,  $t_f \leq$  2 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



# PARAMETER MEASUREMENT INFORMATION $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform22 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \ \Omega$ ,  $t_f \leq 2.5 \ ns$ .
- D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms

www.ti.com 14-Oct-2022

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74ALVTH16601DL	ACTIVE	SSOP	DL	56	20	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ALVTH16601	Samples
SN74ALVTH16601DLR	ACTIVE	SSOP	DL	56	1000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ALVTH16601	Samples
SN74ALVTH16601GR	ACTIVE	TSSOP	DGG	56	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ALVTH16601	Samples
SN74ALVTH16601VR	ACTIVE	TVSOP	DGV	56	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VT601	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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### **PACKAGE OPTION ADDENDUM**

www.ti.com 14-Oct-2022

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 9-Aug-2022

### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74ALVTH16601DLR	SSOP	DL	56	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
SN74ALVTH16601GR	TSSOP	DGG	56	2000	330.0	24.4	8.6	15.6	1.8	12.0	24.0	Q1
SN74ALVTH16601VR	TVSOP	DGV	56	2000	330.0	24.4	6.8	11.7	1.6	12.0	24.0	Q1

www.ti.com 9-Aug-2022



### \*All dimensions are nominal

Device	Package Type	Гуре Package Drawing		SPQ	Length (mm)	Width (mm)	Height (mm)	
SN74ALVTH16601DLR	SSOP	DL	56	1000	367.0	367.0	55.0	
SN74ALVTH16601GR	TSSOP	DGG	56	2000	367.0	367.0	45.0	
SN74ALVTH16601VR	TVSOP	DGV	56	2000	367.0	367.0	45.0	

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 9-Aug-2022

### **TUBE**



### \*All dimensions are nominal

Ì	Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
١	SN74ALVTH16601DL	DL	SSOP	56	20	473.7	14.24	5110	7.87

### DGV (R-PDSO-G\*\*)

### **24 PINS SHOWN**

### **PLASTIC SMALL-OUTLINE**



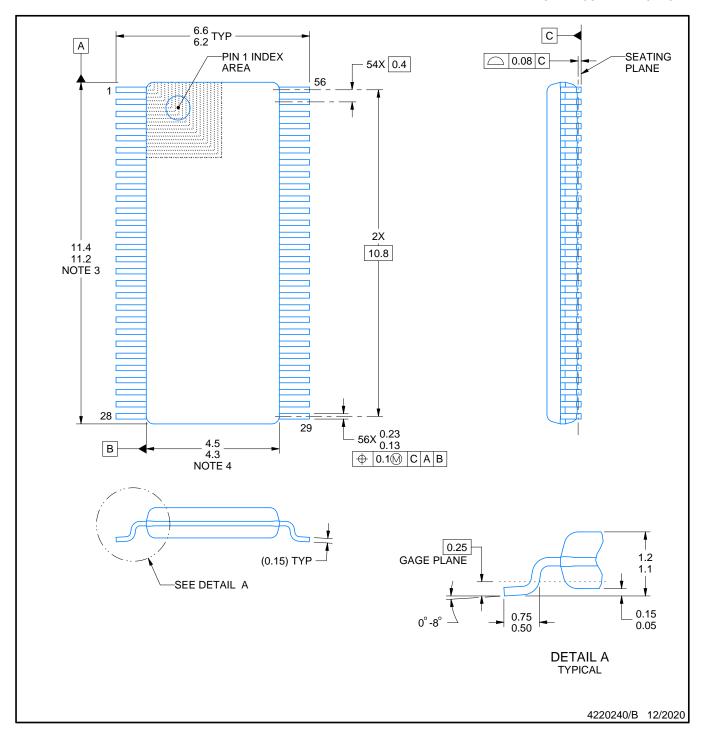
NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194





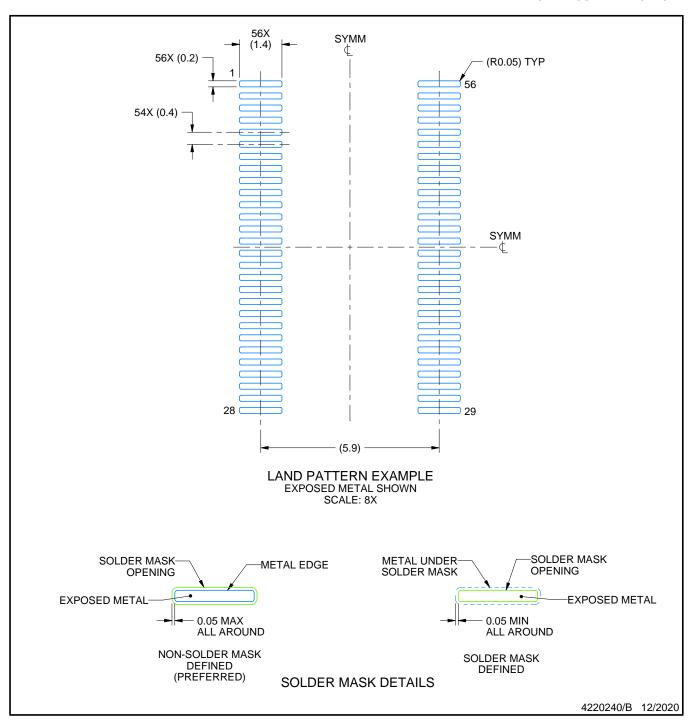
#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-194.



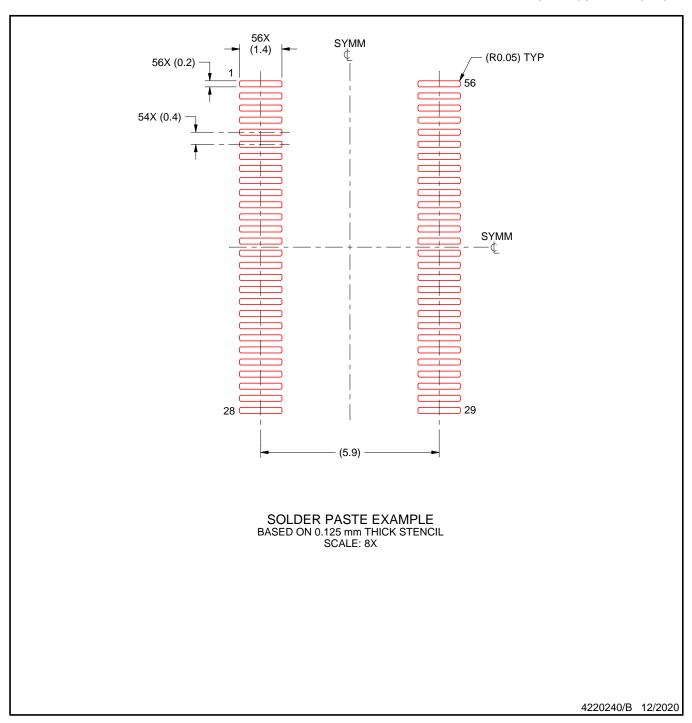


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# DL (R-PDSO-G56)

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MO-118

PowerPAD is a trademark of Texas Instruments.







#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-153.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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